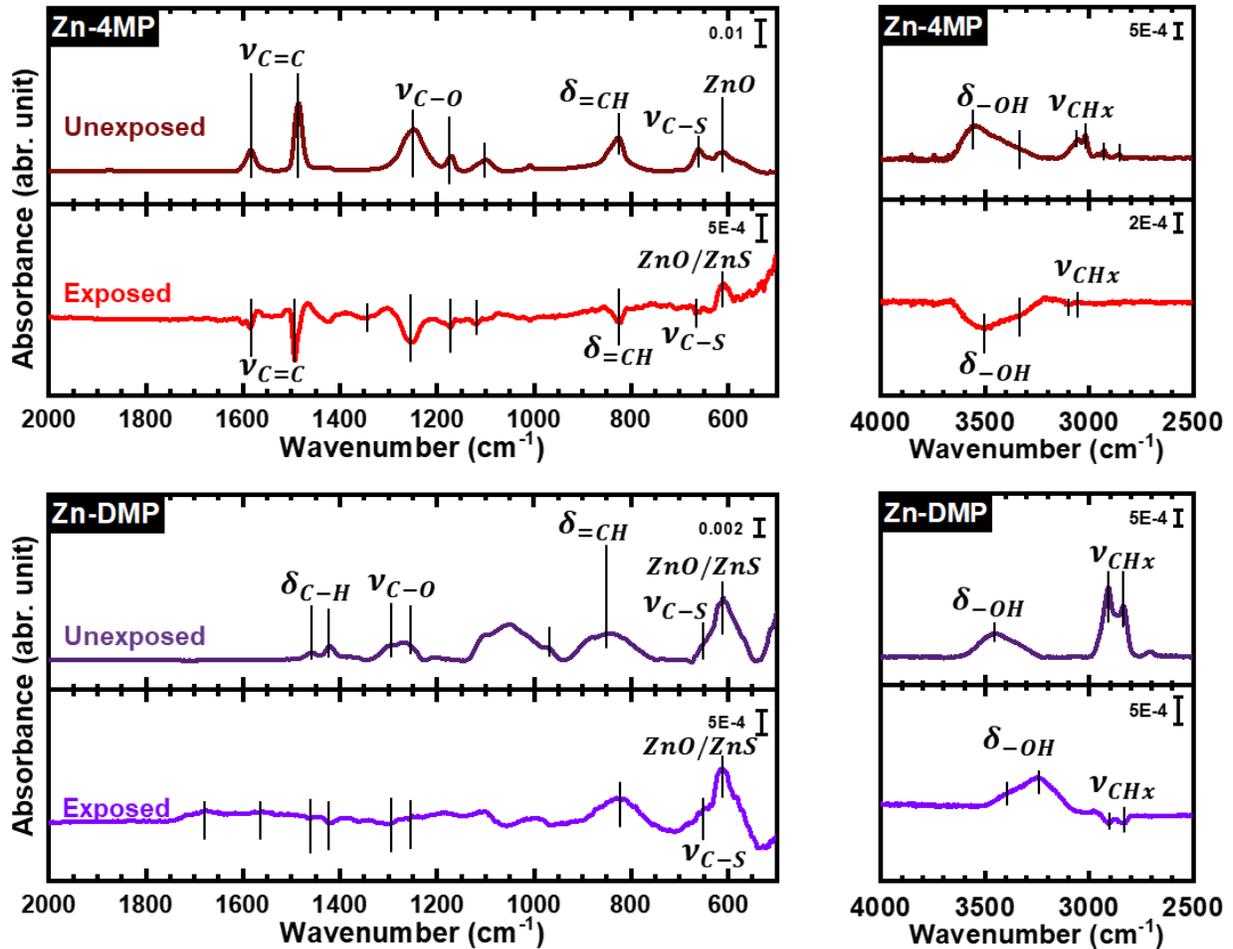


## The Impacts of Organic Structures on the Sensitivity of Molecular Atomic Layer Deposited EUV Resist Thin Films



**Figure 1.** *In-situ* FTIR measurements obtained for Zn-4MP and Zn-DMP, showing changes in chemical bonding before and after low-energy electron exposures.